

**Notice of References Cited**

Application/Control No.

10/568,284

Applicant(s)/Patent Under  
Reexamination  
ONODA ET AL.

Examiner

Thuy N. Pardo

Art Unit

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Page 1 of 1

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*	B	US-2006/0253400	11-2006	Okamoto et al.	705/057
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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